

Sulfuric Acid 96%
CMOS



Material No.: 9684-05
Batch No.: 0000196077
Manufactured Date: 2018/03/19
Expiration Date: 2018/12/17
Revision No: 1


Certificate of Analysis

Test	Specification	Result
Assay (H ₂ SO ₄)	95.0 – 97.0 %	95.7
Color (APHA)	<= 10	5
Residue after Ignition	<= 2 ppm	< 1
Chloride (Cl)	<= 0.1 ppm	< 0.1
Nitrate (NO ₃)	<= 0.2 ppm	< 0.1
Phosphate (PO ₄)	<= 0.3 ppm	< 0.1
Trace Impurities – Aluminum (Al)	<= 50.0 ppb	< 5.0
Arsenic and Antimony (as As)	<= 5 ppb	< 2
Trace Impurities – Barium (Ba)	<= 10.0 ppb	< 1.0
Trace Impurities – Beryllium (Be)	<= 10.0 ppb	< 1.0
Trace Impurities – Bismuth (Bi)	<= 20.0 ppb	< 10.0
Trace Impurities – Boron (B)	<= 10.0 ppb	< 5.0
Trace Impurities – Cadmium (Cd)	<= 10.0 ppb	< 1.0
Trace Impurities – Calcium (Ca)	<= 50.0 ppb	4.1
Trace Impurities – Chromium (Cr)	<= 50.0 ppb	< 1.0
Trace Impurities – Cobalt (Co)	<= 10.0 ppb	< 1.0
Trace Impurities – Copper (Cu)	<= 10.0 ppb	< 1.0
Trace Impurities – Gallium (Ga)	<= 10.0 ppb	< 1.0
Trace Impurities – Germanium (Ge)	<= 10.0 ppb	< 10.0
Trace Impurities – Gold (Au)	<= 20.0 ppb	< 5.0
Heavy Metals (as Pb)	<= 200 ppb	< 100
Trace Impurities – Iron (Fe)	<= 100.0 ppb	1.7
Trace Impurities – Lead (Pb)	<= 20.0 ppb	< 1.0
Trace Impurities – Lithium (Li)	<= 10.0 ppb	< 1.0


Test	Specification	Result
Trace Impurities – Magnesium (Mg)	<= 50.0 ppb	< 1.0
Trace Impurities – Manganese (Mn)	<= 10.0 ppb	< 1.0
Trace Impurities – Mercury (Hg)	<= 5.0 ppb	0.2
Trace Impurities – Molybdenum (Mo)	<= 10.0 ppb	< 5.0
Trace Impurities – Nickel (Ni)	<= 10.0 ppb	< 5.0
Trace Impurities – Niobium (Nb)	<= 10.0 ppb	< 1.0
Trace Impurities – Potassium (K)	<= 50.0 ppb	< 10.0
Trace Impurities – Silicon (Si)	<= 50.0 ppb	< 10.0
Trace Impurities – Silver (Ag)	<= 10.0 ppb	< 1.0
Trace Impurities – Sodium (Na)	<= 100.0 ppb	6.5
Trace Impurities – Strontium (Sr)	<= 10.0 ppb	< 1.0
Trace Impurities – Tantalum (Ta)	<= 10.0 ppb	< 5.0
Trace Impurities – Thallium (Tl)	<= 20.0 ppb	< 5.0
Trace Impurities – Tin (Sn)	<= 50.0 ppb	< 10.0
Trace Impurities – Titanium (Ti)	<= 10.0 ppb	< 1.0
Trace Impurities – Vanadium (V)	<= 10.0 ppb	< 1.0
Trace Impurities – Zinc (Zn)	<= 50.0 ppb	< 1.0
Trace Impurities – Zirconium (Zr)	<= 10.0 ppb	< 1.0
Particle Count – 0.5 µm and greater	<= 60 par/ml	14
Particle Count – 1.0 µm and greater	<= 10 par/ml	3

For Microelectronic Use

Storage Conditions: Recommended Storage Conditions: 15° – 100°F
Country of Origin: US
Packaging Site: Phillipsburg Mfg Ctr & DC



Phillipsburg, NJ 9001:2008, 14001:2004, FSSC 22000
 Paris, KY 9001:2008
 Mexico City, Mexico 9001:2008
 Deventer, The Netherlands 9001:2008, 14001:2004, 13485:2003
 Gliwice, Poland 9001:2008, 13485:2012
 Selangor, Malaysia 9001:2008
 Dehradun, India, 9001:2008, 14001:2004, 13485:2003
 Mumbai, India, 9001:2008
 Panoli, India 9001:2008



Jamie Ethier
 Vice President Global Quality

For questions on this Certificate of Analysis please contact Technical Services at 855.282.6867 or +1.610.573.2600
Avantor Performance Materials, LLC.

3477 Corporate Parkway. Center Valley, PA 18034. U.S.A. Phone: 610.573.2600 . Fax: 610.573.2610